

Notice of References Cited		Application/Control No. 10/646,857	Applicant(s)/Patent Under Reexamination LEE, KEUN BAE	
		Examiner Stephen A Vu	Art Unit 3636	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,273,511	08-2001	Wieclawski, Stanislaw Andrzej	297/463.1
B	US-4,627,661	12-1986	Ronnhult et al.	297/284.4
C	US-6,024,406	02-2000	Charras et al.	297/216.14
D	US-6,499,803	12-2002	Nakane et al.	297/284.4
E	US-6,068,336	05-2000	Schonauer, Alexander	297/284.9
F	US-5,505,520	04-1996	Frusti et al.	297/284.4
G	US-6,199,947	03-2001	Wiklund, Kristina	297/216.12
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
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T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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